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(54) **DIGITAL LOW DROP-OUT VOLTAGE CONTROLLER INCLUDING EMBEDDED DUAL-LOOP FEEDBACK FOR MINIMUM ENERGY POINT OPERATION**

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See application file for complete search history.

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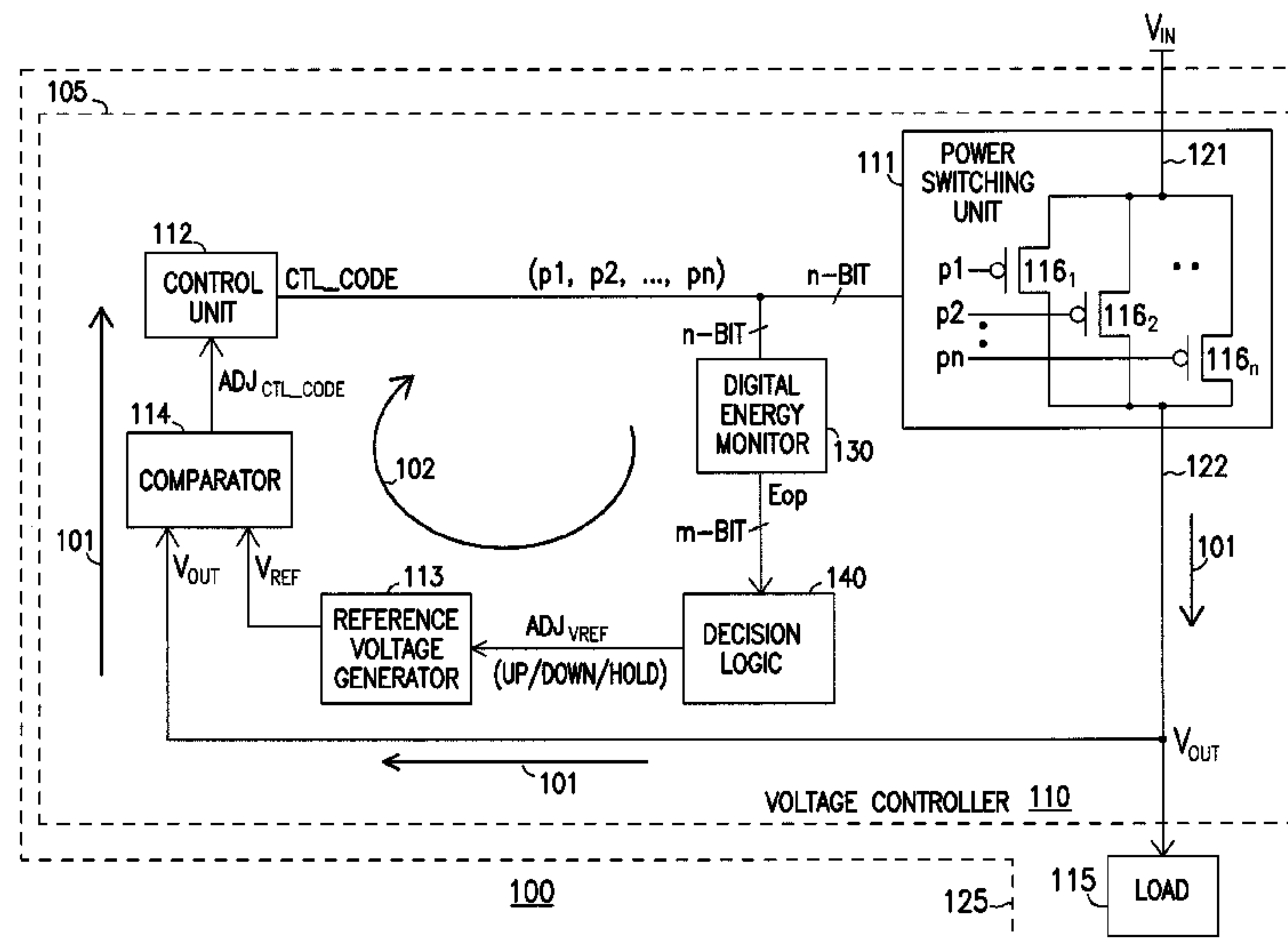
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(57) **ABSTRACT**

Some embodiments include apparatuses and methods having a power switching unit to receive a first voltage and provide a second voltage having a value based on a value of the first voltage, a first loop to provide digital control information to control a switching of the power switching unit in order to maintain a relationship between the value of the second voltage and a value of a reference voltage, and a second loop coupled to the power switching unit and the first loop to calculate a value of energy consumption of at least a portion of the apparatus based at least on the digital control information.

19 Claims, 6 Drawing Sheets



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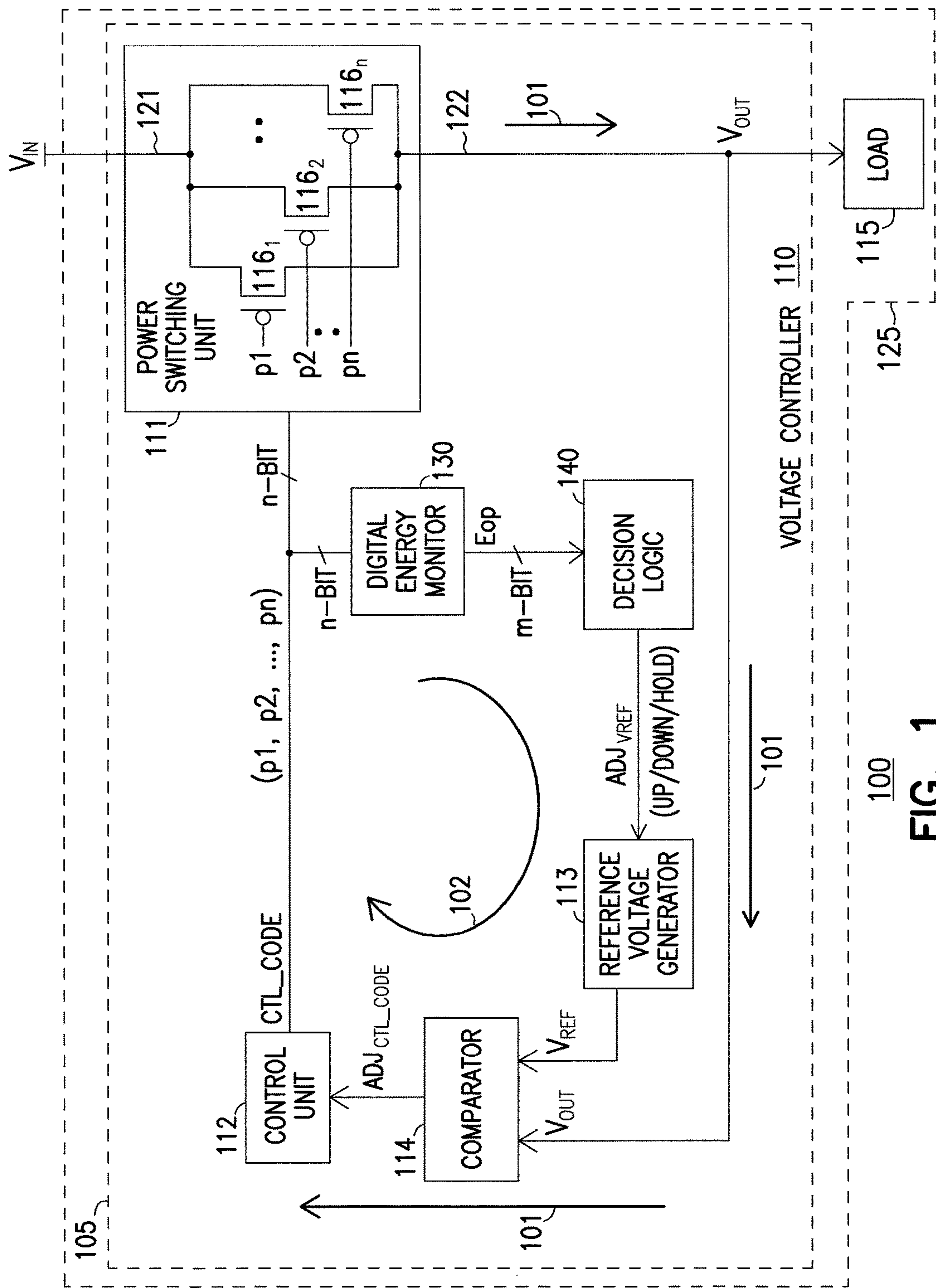
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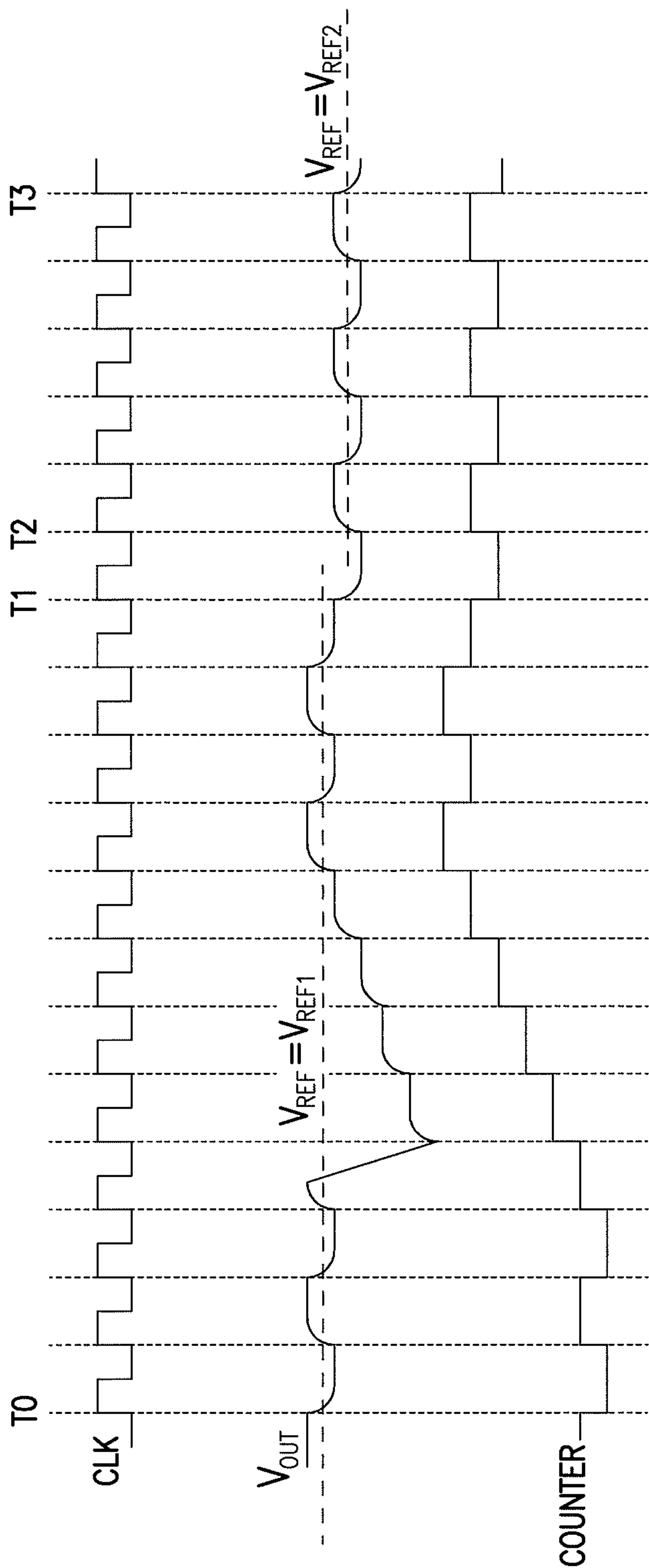


FIG. 2

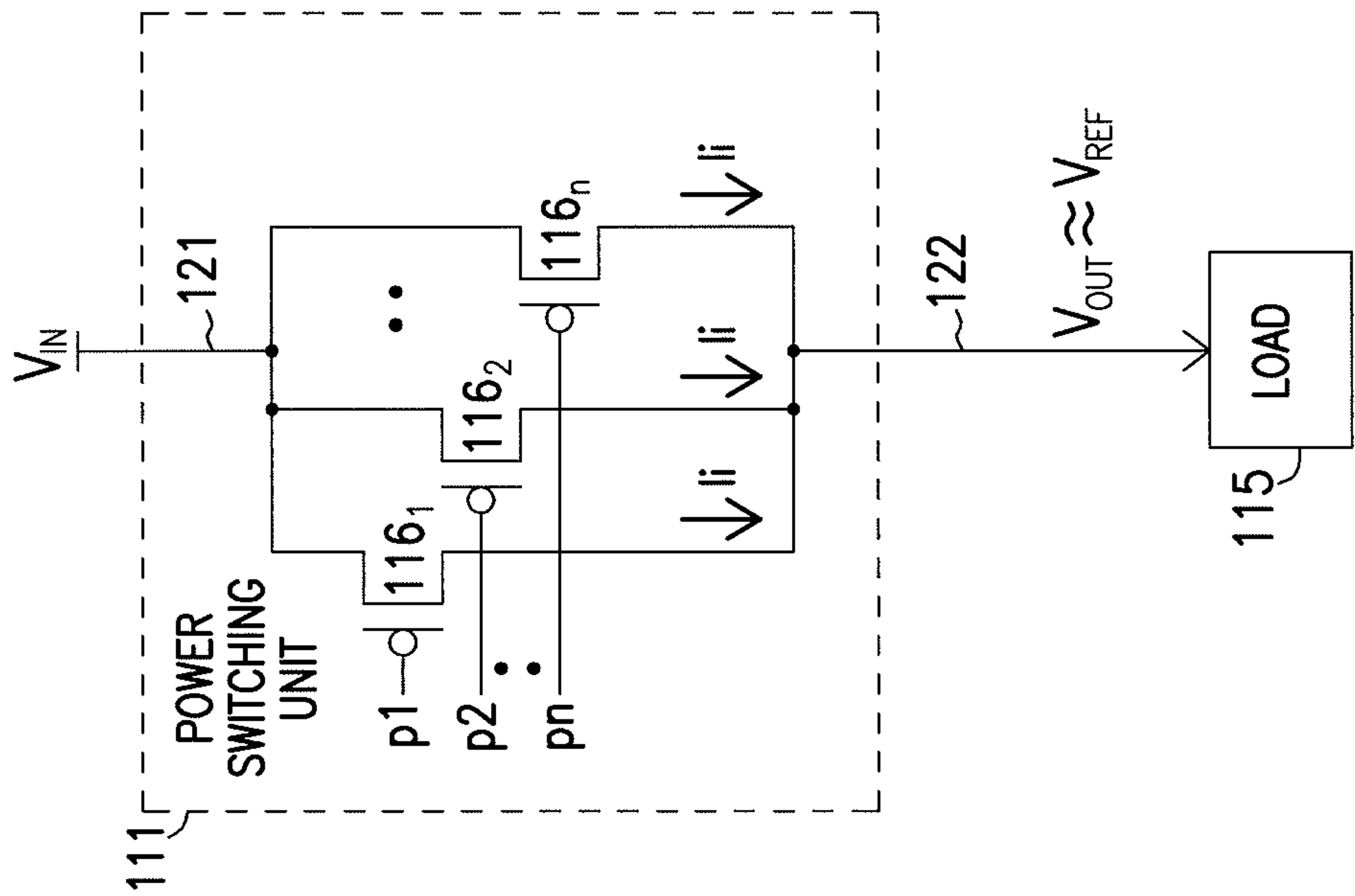
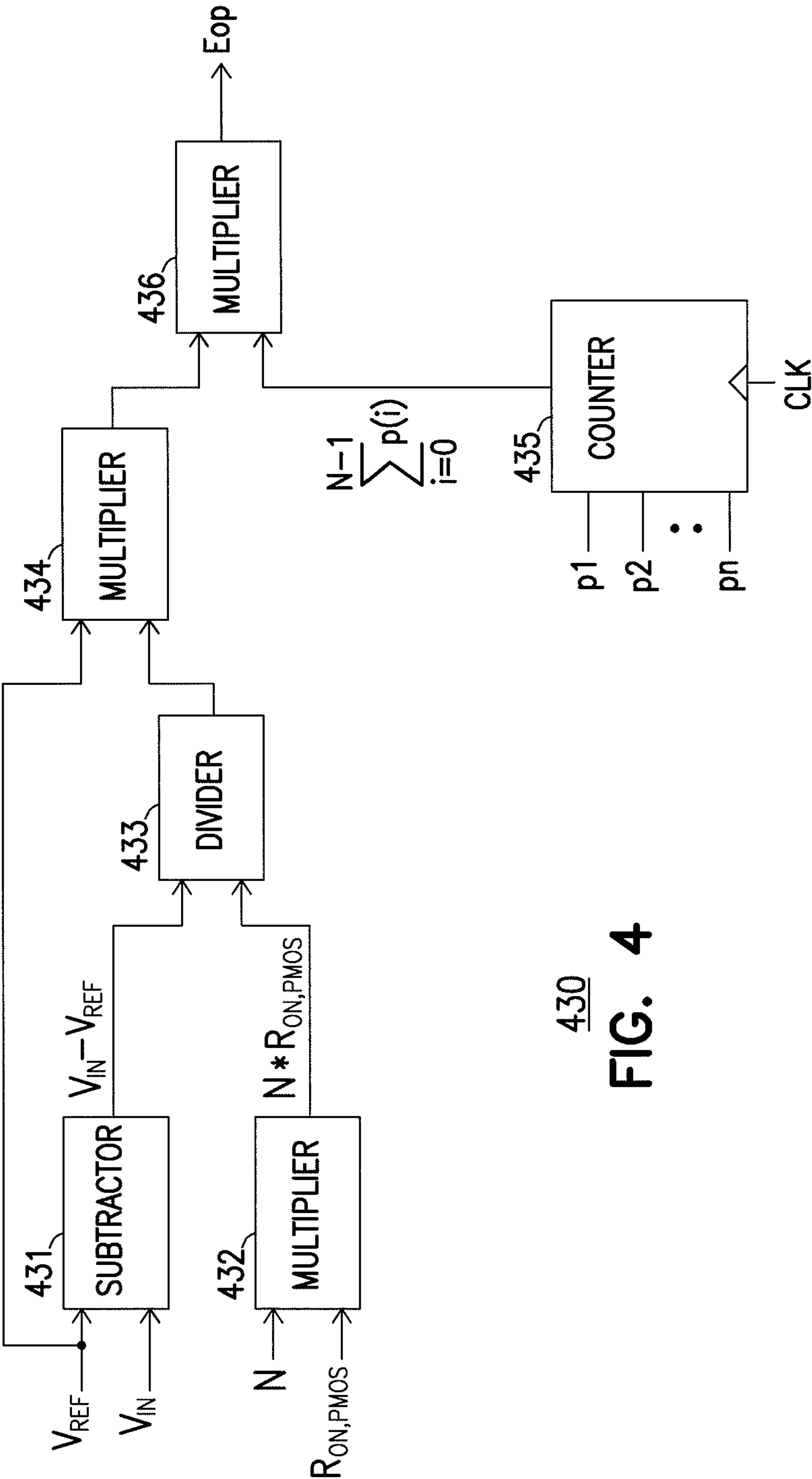


FIG. 3



430
FIG. 4

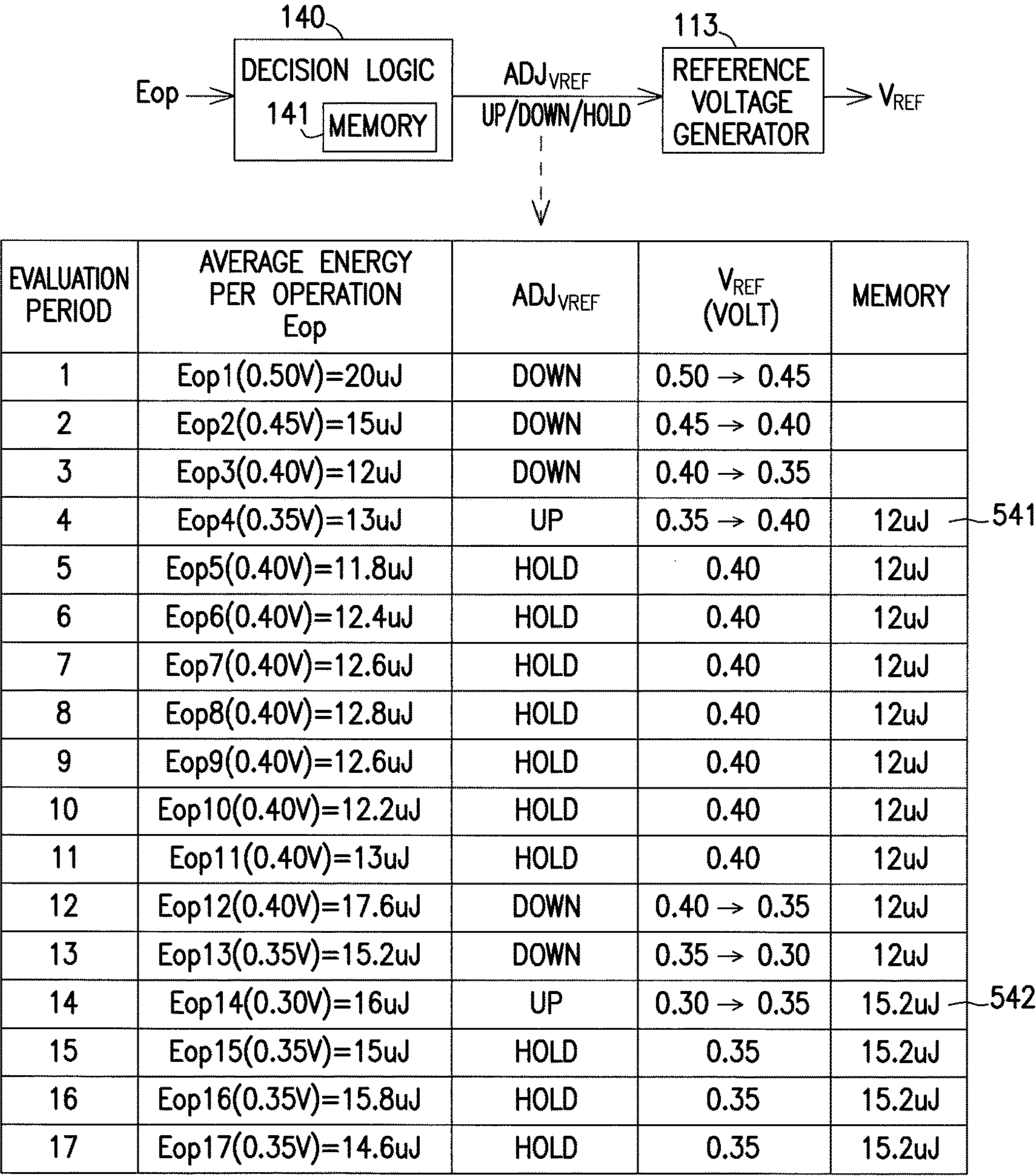
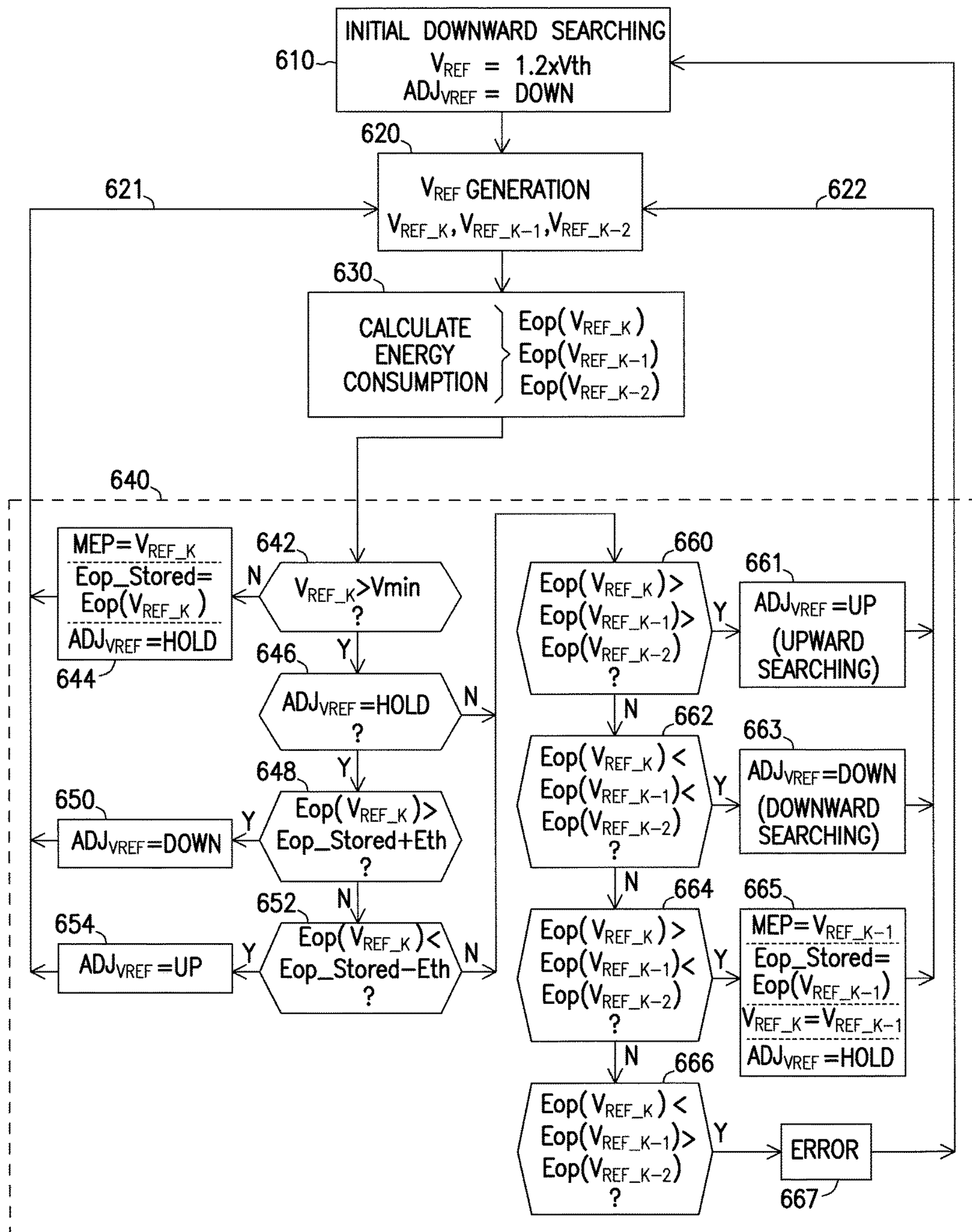


FIG. 5



600
FIG. 6

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DIGITAL LOW DROP-OUT VOLTAGE CONTROLLER INCLUDING EMBEDDED DUAL-LOOP FEEDBACK FOR MINIMUM ENERGY POINT OPERATION

TECHNICAL FIELD

Embodiments described herein pertain to power management in electronic systems. Some embodiments relate to voltage controllers.

BACKGROUND

Many electronic devices or systems, such as computers, tablets, and cellular phones, have a power management unit to control power supply voltage for some circuits (e.g., digital circuits) in the device or system. Conventional techniques are available to enable such circuits to operate at a minimum energy point (MEP). The MEP is the power supply voltage at which the circuit may consume the lowest energy per operation. However, as described in more detail below, some conventional techniques may have drawbacks that may make them unsuitable for some applications.

BRIEF DESCRIPTION OF THE DRAWINGS

FIG. 1 shows an apparatus including a voltage controller and a load, according to some embodiments described herein.

FIG. 2 shows example waveforms for the voltage controller of FIG. 1, according to some embodiments described herein.

FIG. 3 shows a power switching unit of the voltage controller FIG. 1, the load of FIG. 1, and some values used in calculating average energy per operation, according to some embodiments described herein.

FIG. 4 is a block diagram showing a digital energy monitor, according to some embodiments described herein.

FIG. 5 shows a decision logic and a reference voltage generator of the voltage controller of FIG. 1, and an example of finding the MEP in the voltage controller and the load of FIG. 1, according to some embodiments described herein.

FIG. 6 is a flow diagram showing a method of determining MEP in a voltage controller and a load, according to some embodiments described herein.

DETAILED DESCRIPTION

As an operating voltage (e.g., supply voltage) of digital circuits scales down below a threshold voltage (V_{th}), the leakage energy consumed per operation in such digital circuit may start to increase exponentially while the active energy may decrease quadratically. Hence, the total energy consumption may be minimized at a certain voltage value where the leakage energy becomes comparable to the active energy. Such a voltage value may correspond to the lowest point (e.g. a minimum energy point) on a curve that represents a relationship between operating voltage and energy consumption. Operating at the MEP in a particular digital circuit makes that particular digital circuit more energy efficient. The MEP varies depending on operating conditions such as workload, temperature, and V_{th} variations. For example, a workload with higher switching activities may lead to a lower MEP, because higher switching activities may dissipate more active energy without adding to any leakage energy.

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Conventional techniques for finding the MEP at a given operating condition are proposed. However, some conventional techniques may have drawbacks. For example, some conventional techniques for finding MEP may use analog circuit components such as a time based analog-to-digital converter (ADC), a low-offset comparator, or other analog circuitry. Some of these techniques measure a small difference (ΔV) in values of an output voltage used in calculation for finding energy consumption per operation of a particular digital circuit. However, analog circuits used in these techniques may not be synthesizable. Therefore custom design efforts may be needed.

In another example, some conventional techniques may use a sizable off-chip capacitor to minimize the voltage difference (ΔV), because significant voltage drop may incur functionality issues at near-threshold voltage operation. Such an off-chip capacitor may result in board-level area and cost overheads.

Some conventional techniques for finding MEP may track the MEP of a load circuit only. That means that they may not consider the energy overhead of voltage controllers used for dynamic MEP operation. Thus, if the energy loss of voltage controllers is not negligible, the MEP of an entire system (e.g., a load circuit and a voltage controller) may be different from the tracked MEP of only a load circuit. This may result in inefficient MEP tracking.

Other conventional techniques for finding MEP may not provide in-situ (e.g., embedded) MEP tracking capability. That means that they may not dynamically track the MEP without knowledge of workload characteristics. Even if dynamic MEP tracking can be performed in conventional techniques, such techniques may need advanced knowledge of all possible workload conditions. Therefore sizable lookup tables may be needed. In some situations, software-level support may reduce such sizable lookup tables. However, a software solution may be inapplicable for dynamic MEP tracking in some devices or systems because such a solution may cause operational delay (e.g., delay in a path from hardware to software and then back to hardware).

The following description describes an apparatus (e.g., device or system) including a digital voltage controller to provide a supply voltage to a load. The voltage controller can include components (e.g., digital circuitry and logic) to perform improved techniques for tracking and finding the MEP in not only the load, but also the voltage controller.

The improved techniques for tracking and finding the MEP described herein may be fully synthesizable, may enable dynamic MEP tracking without advanced knowledge of workload characteristics of the load, may track the MEP of an entire apparatus or system (e.g., the MEP of the voltage controller and the load). The techniques described herein include components that can be embedded in the voltage controller (e.g., in a digital low drop-out (LDO) regulator). The techniques described herein may avoid an off-chip capacitor, thereby hardware overheads (e.g., power and circuit board area overheads) may be relatively smaller.

FIG. 1 shows an apparatus 100 including a voltage controller 110 and a load 115, according to some embodiments described herein. Apparatus 100 can include or be included in an electronic device or system, such as a computer (e.g., desktop, laptop, or notebook), a tablet, a cellular phone, wearable electronics (e.g., smart watches), or other electronic devices or systems. As described in more detail below, voltage controller 110 can include components (e.g., digital circuitry and logic) to perform improved tech-

niques for tracking and finding the MEP in the entire arrangement **125**, which includes not only load **115**, but also voltage controller **110**.

As shown in FIG. 1, voltage controller **110** can receive a voltage (e.g., input voltage) V_{IN} at a node (e.g., supply node) **121** and provide a voltage (e.g., output voltage or load voltage) V_{OUT} at a node (e.g., output node) **122**. The value of voltage V_{OUT} can be less than the value of voltage V_{IN} by a relatively small amount (e.g., a low drop-out from voltage V_{IN} to voltage V_{OUT}) or a relatively large amount depending on the load operating conditions. Voltage controller **110** includes digital components (described below) to control (e.g., regulate) the value of voltage V_{OUT} , such that voltage controller **110** can be referred to as (e.g. or can operate) as digital LDO voltage controller (or regulator). In some arrangements (e.g., configurations) of voltage controller **110**, voltages V_{IN} and V_{OUT} at node **121** may each have a value of less than 1V (e.g., $V_{IN}=0.6V$ and $V_{OUT}<0.60V$ (e.g., between 0.35V and 0.50)). The value of 1V is used as an example. Voltages V_{IN} and V_{OUT} may have different values.

Load **115** may use voltage V_{OUT} as its operating voltage (e.g., regulated supply voltage). Load **115** can include or be included in a functional unit such as a processor (e.g., a central processing unit (CPU)), a memory device, or other functional (e.g., digital circuits) units.

As shown in FIG. 1, apparatus **100** can include an integrated circuit (IC) die **105** (e.g., an IC chip). The IC die **105** can include a semiconductor die (e.g., a silicon die). Voltage controller **110** can be included in (e.g., integrated in, located on or in, formed in, or formed on) die **105**. Load **115** can be included in another IC die separated from IC die **105**. For example, voltage controller **110** can be included in one IC die on a circuit board (e.g., motherboard), not shown in FIG. 1, and load **115** can be included in another IC die on the circuit board and coupled to voltage controller **110** through conductive traces (e.g., copper trances) on the circuit board.

FIG. 1 shows an example where load **115** is located outside IC die **105**. However, voltage controller **110** and load **115** and can be included in the same IC die.

Apparatus **100** can include or be included in a system on chip (SoC), such that voltage controller **110** and load **115** can be included (e.g., integrated) in the SoC.

As shown in FIG. 1, voltage controller **110** can include a power switching unit **111**, a control unit **112**, a reference voltage generator **113**, and a comparator **114**. Power switching unit **111** can operate to receive voltage V_{IN} provide voltage V_{OUT} . Control unit **112** can operate to generate control information (digital information) CTL_CODE to control (e.g., digitally control) switching of power switching unit **111**. Reference voltage generator **113** can operate to generate a voltage (e.g., reference voltage) V_{REF} . Comparator **114** can operate to compare voltage V_{OUT} with a voltage (e.g., reference voltage) V_{REF} and generate information (e.g., command) ADJ_{CTL_CODE} . Based on information ADJ_{CTL_CODE} , control unit **112** can control (e.g., increase, decrease, or keep the same) the value of control information CTL_CODE.

As shown in FIG. 1, voltage controller **110** can include a loop (e.g., a circuit feedback loop) **101** that can include at least control unit **112** and comparator **114**. Loop **101** can operate to maintain the value of voltage V_{OUT} at approximately the value of a target voltage (e.g., V_{REF}) in order to regulate the value of the load voltage (e.g., voltage V_{OUT}) at node **122**. In operation, comparator **114** of loop **101** can provide information ADJ_{CTL_CODE} based on a comparison (e.g., a difference) between the values of voltages V_{OUT} and V_{REF} . Control unit **112** can control (e.g., increase, decrease,

or keep the same) the value of control information CTL_CODE based on the value of information ADJ_{CTL_CODE} provided by comparator **114**. The operations of control unit **112** and comparator **114** allow loop **101** to maintain the value of voltage V_{OUT} at approximately the value of voltage V_{REF} .

Power switching unit **111** can include transistors (e.g., power transistors) 116_1 through 116_n , arranged (e.g., in parallel) between nodes **121** and **122**. Control unit **112** can include a counter (e.g., n-bit up/down counter) to generate control information CTL_CODE having a number of bits (e.g., n bits), such as bits p1 through pn. Each bit among the bits of control information CTL_CODE may be used to control a gate of a respective transistor among transistors 116_1 through 116_n . Reference voltage generator **113** can include a band-gap based reference voltage generator to generate voltage V_{REF} . Comparator **114** can include a single bit comparator or alternatively a multi-bit analog-to-digital converter (ADC) comparator.

Voltage controller **110** can include a loop (e.g., a circuit feedback loop) **102** to determine the MEP in voltage controller **110** and load **115** at different times. As shown in FIG. 1, a loop **102** can include a digital energy monitor **130** and a decision logic **140**. Digital energy monitor **130** can include digital circuitry that can operate to perform operations (e.g., mathematic operations) to calculate (e.g., evaluate) energy consumption of at least a portion of apparatus **100** (e.g., the portion including arrangement **125** that includes voltage controller **110** and load **115**). The calculation of the energy consumption can include a calculation of average energy per operation Eop of voltage controller **110** and load **115**.

Decision logic **140** can include hardware (e.g., circuitry), software, or a combination of hardware and software to perform local minima searching in order to track and find the MEP of voltage controller **110** and load **115**. For example, based on the energy consumption calculated by digital energy monitor **130**, decision logic **140** can operate to adjust (e.g., dynamically adjust) the value of voltage V_{REF} in order to track and find the MEP of voltage controller **110** and load **115**. A detailed description of loop **102** (e.g., digital energy monitor **130** and a decision logic **140**) is below (FIG. 3, FIG. 4, and FIG. 5) after the description of FIG. 2.

FIG. 2 shows example waveforms for voltage controller **110** of FIG. 1, according to some embodiments described herein. In FIG. 2, voltages V_{REF1} and V_{REF2} represent voltage V_{REF} (FIG. 1) generated by reference voltage generator **113** at different times. For example, between times T0 and T1, reference voltage generator **113** (FIG. 1) may generate voltage V_{REF} (represented by V_{REF1} in FIG. 2) having a value of 0.40V and hold it at 0.40V. Between times T2 and T3, reference voltage generator **113** may generate voltage V_{REF} (represented by V_{REF1} in FIG. 2) having another value (e.g., new value) of 0.35V and hold it at 0.35V.

Between times T0 and T1, the value of voltage V_{OUT} may be maintained by loop **101** (FIG. 1), such that the value of voltage V_{OUT} can be approximately equal to the value of voltage V_{REF} (e.g., at $V_{REF1}=0.40V$) in order to regulate the value of the load voltage (e.g., voltage V_{OUT}) at node **122** (FIG. 1).

Between times T1 and T2, the value of V_{REF1} changes to the value of V_{REF2} . This indicates that loop **102** (FIG. 1) of voltage controller **110** may cause reference voltage generator **113** to generate a new value (e.g., 0.35V) as part of an operation to track the MEP of voltage controller **110** and load **115**.

Between times T2 and T3, loop **101** operates in a similar way as between times T0 and T1. For example, as shown in

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FIG. 2, between times T2 and T3, the value of voltage V_{OUT} may be maintained by loop 101 (FIG. 1), such that the value of voltage V_{OUT} can be approximately equal to the value of voltage V_{REF} (e.g., at $V_{REF2}=0.35V$) in order to regulate the value of the load voltage (e.g., voltage V_{OUT}) at node 122 (FIG. 1).

The example of FIG. 2 shows waveforms associated with only a portion of the operations of voltage controller 110 of FIG. 1, where reference voltage generator 113 generates voltage V_{REF} having two different values (e.g., 0.40V and 0.35V) at different times. However, reference voltage generator 113 can generate voltage V_{REF} having more than two different values between times T0 and T3, depending on the number of MEPs found by voltage controller 110 between times T0 and T3.

After time T3, the waveform for the rest of the operations of voltage controller 110 may follow a similar pattern between times T0 and T3. For example, after time T3, if loop 102 (FIG. 1) finds a new MEP at a particular value of V_{REF} (e.g., a value different from $V_{REF2}=0.35V$ or 0.40V), then loop 102 may cause reference voltage generator 113 to generate voltage V_{REF} with that particular value.

The clock signal CLK in FIG. 2 is a timing signal that may be used by a counter in control unit 112 to adjust (e.g., increase (e.g., count up) or decrease (e.g., countdown)) the value of control information CTL_CODE. This allows control unit 112 to control power switching unit 111 (e.g., change the number of transistors 116₁ through 116_n that are turned on) in order to maintain the value of voltage V_{OUT} to be approximately equal to the value of voltage V_{REF} (e.g., V_{REF1} or V_{REF2} in FIG. 2).

In the example of FIG. 2, the value of voltage V_{REF} held at V_{REF1} (e.g., 0.40V) between times T0 and T1 and at V_{REF2} (e.g., 0.35V) between times T2 and T3 may indicate that two MEPs (associated V_{REF1} and V_{REF2}) may have been found by loop 102. For example, before time T0, loop 102 may find the MEP when $V_{REF}=V_{REF1}$. In another example, between times T1 and T2, loop 102 may find the MEP when $V_{REF}=V_{REF2}$.

Tracking of the MEP by voltage controller 110 can include calculating (e.g., performed by digital energy monitor 130 of FIG. 1) and then comparing (e.g., performed by decision logic 140 of FIG. 1) an average energy per operation Eop of voltage controller 110 and load 115 in an energy evaluation (e.g., calculation) period with one or more average energy per operation Eop of voltage controller 110 and load 115 in other evaluation periods.

FIG. 3 shows power switching unit 111 and load 115 of FIG. 1 and some values used in calculating average energy per operation Eop, according to some embodiments described herein. In FIG. 3, each of transistors 116₁ through 116_n can include a power transistor, such as a p-channel transistor (e.g., p-channel metal oxide semiconductor (PMOS) power transistor). Current I_i indicates a current flowing through a particular transistor among transistors 116₁ through 116_n in a particular cycle (e.g., cycle “i” of a clock signal) if that particular transistor is turned on during that cycle. Current I_i may not flow through a particular transistor among transistors 116₁ through 116_n if that particular transistor is turned off.

In a particular cycle, some of transistors 116₁ through 116_n may be turned on while the rest of transistors 116₁ through 116_n may be turned off, depending on the energy consumed by voltage controller 110 and load 115 at that particular cycle. The number transistors among transistors 116₁ through 116_n that are turned on may be different from

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one cycle to the next cycle, depending on energy consumed by voltage controller 110 and load 115.

Each of transistors 116₁ through 116_n may be turned on or turned off based on the value of a corresponding bit (e.g., one of p1 through pn) of control information CTL_CODE. The number of bits (e.g., n bits) of control information CTL_CODE can be equal to the number (e.g., n) of transistors 116₁ through 116_n. For example, if the number of transistors 116₁ through 116_n is 16 (e.g., n=16), then control information CTL_CODE can have 16 bits to control the corresponding gates of 16 transistors 116₁ through 116_n (in order to turn on or turn off the transistors).

Since transistors 116₁ through 116_n are PMOS transistors, a particular transistor among transistors 116₁ through 116_n can be turned on if the bit controlling its gate has a value of binary zero (“0”) and turned off if the bit has value of binary one (“1”). As an example, during a particular cycle, if the values (binary values) of p1, p2, . . . , pn are “11, . . . , 0”, then transistors 116₁ and 116₂ are turned off and transistor 116_n is turned on during that particular cycle.

Calculation (e.g., evaluation) of energy consumed by voltage controller 110 and load 115 can be based at least in part on the switching (e.g., turning on and turning off) of transistor 116₁ and 116_n. In the calculation of energy described below, the size of transistors 116₁ through 116_n is assumed to be the same (e.g., same weight). However, in some cases, transistors 116₁ through 116_n can have different sizes (e.g., different weights, such as binary weighed transistors). In such cases, the calculation of energy associated with formula (1) below may be modified accordingly without departing from the scope of the subject matter described herein.

The description associated with FIG. 3 describes calculation of an average energy per operation Eop consumed by voltage controller 110 and load 115 (FIG. 1) during N cycles (e.g., N cycles of clock signal CLK). The energy per operation of voltage controller 110 and load 115 can include the energy consumed by voltage controller 110 and load 115 in one cycle of a clock signal (e.g., CLK in FIG. 2). Thus, average energy per operation Eop of voltage controller 110 and load 115 can include an energy per cycle consumed by voltage controller 110 and load 115. The value (e.g., in Joule unit) of the average energy per operation Eop can be represented by digital information (e.g., digital code) that includes a number of bits (e.g., m bits as shown in FIG. 1).

In order to find the MEP of voltage controller 110 and load 115 (FIG. 1), digital energy monitor 130 may calculate many average energy per operations (many Eops) for many different N cycles. For example, if N is set at 1000, then digital energy monitor 130 may calculate Eop1 (one average energy per operation) during 1000 cycles, calculate Eop2 (another average energy per operation) during another 1000 cycles, calculate Eop3 (another average energy per operation) during another 1000 cycles, and so on. Decision logic 140 can operate (as described in detail with reference to FIG. 5) to find the MEP of voltage controller 110 and load 115 based on the different average energy per operations (e.g., Eop1, Eop2, and Eop3, and so on) calculated by digital energy monitor 130.

In FIG. 3, the average energy per operation (e.g., one of Eop1, Eop2, and Eop3 in the above example) for particular N cycles is calculated (e.g., digitally calculated) as follows:

$$Eop_j = \frac{1}{N} \sum_{i=0}^{N-1} p(i) \times I_i \times V_{IN} + \frac{1}{N} \sum_{i=0}^{N-1} p(i) \times \frac{(V_{IN} - V_{OUT})}{R_{ON,PMOS}} \times V_{IN} \quad (1)$$

$$\cong \frac{(V_{OUT} - V_{IN})}{N \times R_{ON,PMOS}} \times \sum_{i=0}^{N-1} p(i)$$

In formula (1) the average energy per operation Eop_j is the average energy per operation consumed by voltage controller **110** and load **115** during an evaluation period (e.g., evaluation period j). Each evaluation period is N cycles. For example, if $N=1000$ cycles and the total energy consumed by voltage controller **110** and load **115** during $N=1000$ cycles is 14,000 uJ (micro-Joule), then the average energy per operation (e.g., per cycle) during this 1000 cycles in this example is 14,000 uJ/1000=14 uJ. Thus, the energy per operation Eop_j is equal to the total energy of N cycles calculated during an evaluation period (e.g., during $N=1000$ cycles) divided by the number of cycles (e.g., divided by 1000) used to calculate the total energy calculated in the evaluation period.

In the formula (1), $p(i)$ is a vector having components represented by bits p_1 through p_n (e.g., vector $p_i = [p_1, p_1, \dots, p_n]$). In a particular cycle (e.g., cycle i) the value of vector $p(i)$ can be based on the values of the number of bits (among bits of control information CTL_CODE of FIG. 1) that cause a corresponding transistor among transistors **116₁** through **116_n** to turn on. As described above, each of transistors **116₁** through **116_n** is a PMOS transistor that can be turned on by a corresponding bit (e.g., one of bits p_1 through p_n) that has a value of “0” (binary zero). Thus, the value of vector $p(i)$ can be obtained by counting the number of bits (among the bits of control information CTL_CODE) that have “0” values. For example, if control information CTL_CODE has 16 bits and the values (binary values) of the 16 bits are “111111111000000”, then the value of vector $p(i)$ in this example is six (the number of “0”s in “111111111000000”).

The value of N in formula (1) is the number of cycles (e.g., cycles of clock signal CLK) used for each energy evaluation period. The value of N can be programmable. The value of N is a digital value that can be set at a value that may depend on workload length, scale, or both, of load **115**. For example, as described above, the value of N can be set at 1000 (or at another number).

Voltage V_{IN} can be the supply voltage of voltage controller **110**. Thus, the value of voltage V_{IN} is a known value. The value of voltage V_{IN} can be a digital value (e.g., digital code) that can be determined by overall system requirements (dynamic voltage and frequency scaling (DVFS)) of the system that includes voltage controller **110**.

As shown in FIG. 3, voltage V_{OUT} at node **122** can be assumed to be approximately equal to the value of voltage V_{REF} for a large number of N . Thus, in formula (1) above, voltage V_{OUT} can be substituted by voltage V_{REF} .

Voltage V_{REF} is the voltage generated by reference voltage generator **113** (FIG. 1). Different evaluation periods may have different values of V_{REF} . For example, in one energy evaluation period (e.g., during $N=1000$ cycles), voltage V_{REF} may have a value of 0.45V. During another evaluation period (e.g., another $N=1000$ cycles), voltage V_{REF} may have a value of 0.40V. The value of voltage V_{REF} can be a digital value (e.g., digital code) given by a minimum steps of voltage controller **110** (e.g., a minimum LDO step of 50 mV). Different values of V_{REF} have different digital codes.

The value of resistance $R_{ON,PMOS}$ (on-resistance) is based on the resistance of a PMOS transistor (e.g., transistors **116₁** through **116_n**) when it is turned on. The size of each of transistors **116₁** through **116_n** can be relatively large in order to provide enough current for load **115** (FIG. 1). Thus, the value of $R_{ON,PMOS}$ of transistors **116₁** through **116_n** may hardly be influenced by process variation. Therefore, the value of $R_{ON,PMOS}$ of transistors **116₁** through **116_n** can be a digital value and can be determined at design phase (this means that any post-silicon tuning processes may be omitted). However, in voltage controller **110**, the value of resistance $R_{ON,PMOS}$ of each of transistors **116₁** through **116_n** may be dependent on its drain voltage (e.g., voltage V_{REF} at node **122**). The values of $R_{ON,PMOS}$ of transistors **116₁** through **116_n** can have multiple digital codes mapping to respective values of voltage V_{REF} .

The value of summation

$$\sum_{i=0}^{N-1} p(i)$$

can be based on the values of the number of bits (among bits of control information CTL_CODE of FIG. 1) that cause a corresponding transistor among transistors **116₁** through **116_n** to turn on during N cycles. Thus, the value of this summation can be obtained by counting the number of bits (among the bits of control information CTL_CODE) that have “0” values during N cycle.

As described above, during a particular cycle i , some of transistors **116₁** through **116_n** may be turned on and some may be turned off. For energy evaluation, some values of $p(i)$ in

$$\sum_{i=0}^{N-1} p(i)$$

may be omitted from the calculation of this summation. For example, digital energy monitor **130** of FIG. 1 may not need to check (e.g., monitor) all values of $p(i)$. Instead, digital energy monitor **130** may check only the bits of control information CTL_CODE that have “0” values and ignore bits having “1” values. Checking bits having “0” value may be achieved by using a counter (e.g., a simple up counter to count the number of “0” in the bits of control information CTL_CODE). For example, in a particular cycle i , if the number of transistors **116₁** through **116_n** is 16 (e.g., $n=16$), and 16 bits of control information CTL_CODE (controlling the 16 transistors) include 6 bits having value “0” and 11 bits having value “1”, then the value of $p(i)$ to be checked (e.g., counted) in that particular is six. Digital energy monitor **130** can use a counter to add the number of “0” from each cycle of the N cycles to provide the value for

$$\sum_{i=0}^{N-1} p(i).$$

Thus, as described above, all of the terms N , V_{IN} , V_{REF} , $R_{ON,PMOS}$, and $\sum p(i)$ in formula (1) can have digital values (e.g., digital codes). Therefore, energy evaluation to determine the value of average energy per operation Eop of

voltage controller **110** and load **115** can be digitally implemented. For example, based on formula (1), simple digital circuitry can be used, such as a counter for $\Sigma p(i)$ calculation, dedicated computation unit for one subtraction, three multiplications, and one division. In comparison with some conventional energy calculation techniques, the digital implementation may allow the circuit arrangement of voltage controller **110** to be less complicated, more accurate, easier to synthesize, or all of these improvements. Since loop **102** is embedded in (e.g., in situ) voltage controller **110**, loop **102** may perform the calculation of energy consumption of voltage controller **110** and load **115** without using a capacitor coupled to load **115** (e.g., without using an off-chip capacitor coupled to node **122** of FIG. 1). Further, since loop **102** is embedded in voltage controller **110**, load **115** can remain coupled to node **122** during the calculation of energy consumption in voltage controller **110** and load **115**.

FIG. 4 is a block diagram showing a digital energy monitor **430**, according to some embodiments described herein. Digital energy monitor **430** can be used as digital energy monitor **130** of FIG. 1. Digital energy monitor **430** of FIG. 4 can operate to evaluate energy per operation Eop described above with reference to FIG. 3.

As shown in FIG. 4, digital energy monitor **430** can include inputs (e.g., input nodes) to receive the digital values (e.g., digital codes) of V_{REF} , V_{IN} , N , $R_{ON,PMOS}$, and digital value (e.g., "0" or "1") of the components (e.g., p_1 through p_n) of vector $p(i)$. Based on formula (1), digital energy monitor **430** can perform math operations on these digital values and provide average energy per operation Eop (represented by Eopj in formula (1)) at the output (e.g., output node or nodes) of digital energy monitor **430**.

As shown in FIG. 4, digital energy monitor **430** can include a subtractor (e.g., circuit) **431** to perform a subtraction operation $V_{IN} - V_{REF}$, a multiplier (e.g., circuit) **432** to perform a multiplication operation $N \times R_{ON,PMOS}$, a divider (e.g., circuit) **433** to perform a division operation $(V_{IN} - V_{REF}) / (N \times R_{ON,PMOS})$, and a multiplier (e.g., circuit) **434** to perform a multiplication operation $V_{REF} \times [(V_{IN} - V_{REF}) / (N \times R_{ON,PMOS})]$.

As shown in FIG. 4, digital energy monitor **430** can also include a counter **435** and a multiplier (e.g., circuit) **436**. Counter **435** can operate to count the number of bits among bits p_1 through p_n that have a value of "0". Counter **435** may perform the count operation based on timing (e.g., based on the cycles of a clock cycle CLK). Multiplier (e.g., circuit) **436** can perform a multiplication operation on a digital value $\{V_{REF} \times [(V_{IN} - V_{REF}) / (N \times R_{ON,PMOS})]\}$ from outputs of counter **435** and multiplier **436**.

The value of energy per operation Eop calculated from one evaluation period may be different from the value of energy per operation Eop calculated from another evaluation period. Based on the value of energy per operation Eop from each of the evaluation periods calculated by digital energy monitor **430**, decision logic **140** can operate to find the MEP of voltage controller **110** and load **115**.

FIG. 5 shows decision logic **140** and reference voltage generator **113** of FIG. 1 and an example of finding the MEP in voltage controller **110** and load **115**, according to some embodiments described herein. FIG. 5 shows an example of 17 evaluation periods 1 through 17 and corresponding 17 average energy per operations Eop1 through Eop17 calculated by digital energy monitor **130**. Decision logic **140** can use average energy per operations Eop1 through Eop17 to find the MEPs in voltage controller **110** and load **115**.

Each of evaluation periods 1 through 17 can be N cycles (e.g., N=1000 cycles), as described above. Digital energy

monitor **130** (FIG. 1) may sequentially perform evaluation periods 1 through 17 to calculate average energy per operations Eop1 through Eop17, respectively.

The value of each of average energy per operation Eop1 through Eop17 is measured in Joule units, such as in micro-Joule (uJ) units, in the example of FIG. 5. The values (in uJ) of average energy per operations Eop1 through Eop17 may be the same or different, depending on operating conditions of voltage generator **110** and load **115**. The value (in volts) of voltage V_{REF} used for calculation of average energy per operations Eop1 through Eop17 from one evaluation period to the next may be the same or different.

The values in FIG. 5 are described as follows. For example, evaluation period 1, Eop1=Eop (0.50V)=20 uJ/cycle, indicates that the average energy per operation (Eop1) during evaluation period 1 (during N cycles) is 20 uJ, which is calculated by digital energy monitor **130** at the value of $V_{REF}=0.50V$. In another example, evaluation period 2, Eop2=Eop (0.45V)=15 uJ/cycle, indicates that the average energy per operation (Eop2) during evaluation period 2 (during N cycles) is 15 uJ, which is calculated by digital energy monitor **130** using the value of $V_{REF}=0.45V$.

The UP/DOWN/HOLD directions represent the directions that decision logic **140** used to control (e.g., increase, decrease, or keep the same) the value of information ADJ_{VREF} . Based on the UP/DOWN/HOLD directions, reference voltage generator **113** can control (e.g., increase, decrease, or keep the same) the value of voltage V_{REF} accordingly. For example, the UP and DOWN directions can cause reference voltage generator **113** to increase and decrease, respectively, the value of V_{REF} . The HOLD direction can cause reference voltage generator **113** to keep the value of V_{REF} at the same value. In the example of FIG. 5, the value of V_{REF} can be adjusted (e.g., increased or decreased) by 50 mV (millivolts) at a time (e.g., a minimum LDO step of 50 mV). However, the same value of voltage V_{REF} may result in different values (in micro-Joule) of average energy per operation calculated by digital energy monitor **130**, depending on the operating conditions of voltage generator **110** and load **115** at the time a particular average energy per operation is calculated.

In the example associated with FIG. 5, decision logic **140** is assumed to be configured such that at the start of the operation of finding MEP (before an initial MEP associated with a local minima is found), if an initial value of voltage V_{REF} is greater than the value of the threshold voltage (e.g., V_{th} of transistors **116**₁ through **116**_n), then decision logic **140** can adjust (e.g., change) the value of information ADJ_{VREF} in the DOWN direction at the start of finding the initial MEP. In FIG. 5, reference voltage generator **113** is assumed to be configured to generate voltage V_{REF} having an initial value (e.g., a value before evaluation period 1) greater than the value of V_{th} . For example, the initial value of V_{REF} may be set to be $V_{REF}(\text{initial})=1.2 \times V_{th}$, where V_{th} can be between 0.3V and 0.4V. Based on these assumptions, an initial MEP and subsequent MEP (or MEPs) can be determined (e.g., found) by decision logic **140** as follows.

As shown in FIG. 5, in evaluation period 1, the value of average energy per operation (e.g., initial) Eop1 is 20 uJ. Thus, the direction (e.g., initial direction at the start of finding the MEP) for the value of information ADJ_{VREF} associated with Eop1 is the DOWN direction because the value (e.g., initial value) of V_{REF} is 0.50V, which is greater than the value of V_{th} (e.g., between 0.30V and 0.40V) as assumed above. Therefore, an initial direction (e.g., DOWN) for the value of information ADJ_{VREF} associated with Eop1 may be based on the value of voltage V_{REF} (and not based

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on the value (20 uJ) of Eop1. However, subsequent directions for the value of information ADJ_{VREF} (e.g., associated with Eop2 through Eop17) can be based on the values (e.g., uJ) of subsequent average energy per operations. In response to the value of information ADJ_{VREF} being adjusted in the DOWN direction based on Eop1 (0.50V)=20 uJ/cycle, reference voltage generator 113 changes the value of V_{REF} in the same direction (DOWN). Thus, as shown in FIG. 5, the value of V_{REF} is changed from 0.50V to 0.45V (e.g., LDO step voltage of 50 mV). The example of FIG. 5 uses 50 mV (LDO step voltage of 50 mV) as an example. Another value for the step voltage may be used.

In evaluation period 2, the value of average energy per operation Eop2 is 15 uJ (Eop2 (0.45V)=15 uJ/cycle). Decision logic 140 compares this value (15 uJ) with the previous value (value of Eop1) and detects a decrease in the value of average energy per operation (e.g., from Eop1=20 uJ to Eop2=15 uJ). The decrease in the average energy per operation may indicate that 15 uJ may be the MEP (e.g., associated with a local minima). However, in order to determine whether 15 uJ can be considered as the MEP (the initial MEP in this example), decision logic 140 adjusts the value of information ADJ_{VREF} in the DOWN direction. Then, decision logic 140 continues to compare the present average energy per operation (e.g., Eop2=15 uJ) with the value of next average energy per operation (e.g., Eop3) in the next evaluation period (e.g., evaluation period 3). In response to the value of information ADJ_{VREF} being adjusted in the DOWN direction based on Eop2 (0.45V)=15 uJ/cycle, reference voltage generator 113 changes the value of V_{REF} in the same direction (DOWN). Thus, as shown in FIG. 5, the value of V_{REF} is changed from 0.45V to 0.40V. This 0.40V value of voltage V_{REF} is used in the calculation of the next average energy per operation (e.g., Eop3).

In evaluation period 3, the value of average energy per operation Eop3 is 12 uJ (Eop3 (0.40V)=12 uJ/cycle). Decision logic 140 compares this value with the previous value (value of Eop2) and detects a decrease in the value of average energy per operation (e.g., from Eop2=15 uJ to Eop3=12 uJ). This decrease in average energy per operation is similar to the previous situation (from Eop1=20 uJ to Eop2=15.0 uJ). The decrease in the average energy per operation may indicate that 12 uJ may be the MEP. However, similarly to the previous situation, in order to determine whether 12 uJ can be considered as the MEP (the initial MEP in this example), decision logic 140 adjusts the value of information ADJ_{VREF} in the DOWN direction. Then, decision logic 140 continues to compare the present average energy per operation (e.g., Eop3=12 uJ) with the value of the next average energy per operation (e.g., Eop4) in the next evaluation period (e.g., evaluation period 4). In response to the value of information ADJ_{VREF} being adjusted in the DOWN direction based on Eop3 (0.45V)=15 uJ/cycle, reference voltage generator 113 changes the value of V_{REF} in the same direction (DOWN). Thus, as shown in FIG. 5, the value of V_{REF} is changed from 0.40V to 0.35V. This 0.35V value of voltage V_{REF} is used in the calculation of the next average energy per operation (e.g., Eop4).

In evaluation period 4, the value of average energy per operation Eop4 is 13 uJ. Decision logic 140 compares this value with the previous value (Eop3=12 uJ) and detects an increase in the value of average energy per operation (e.g., from Eop3=12 uJ to Eop4=13 uJ). This increase in average energy per operation (e.g., from Eop3=12 uJ to Eop4=13 uJ) indicates that the previous value of average energy per operation (Eop3=12 uJ) may be considered as the MEP (an initial MEP in this example). Thus, in response to the

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increase in the value of average energy per operation, decision logic 140 determines that the MEP (Eop3=12 uJ) is considered to be found.

As shown in FIG. 5, decision logic 140 may perform an operation (e.g., operation 541) to store (e.g., in memory 141) the value (e.g., 12 uJ) of the average energy per operation that is considered as the MEP. FIG. 5 shows memory 141 being inside decision logic 140 as an example. However, memory 141 may be located at another location in voltage controller 110. After the MEP is found, Decision logic 140 also adjusts the value of information ADJ_{VREF} to cause reference voltage generator 113 to change the value of V_{REF} to the value (e.g., 0.40V associated with Eop3) at which the MEP is considered to be found. Thus, in this example, decision logic 140 adjusts the value of information ADJ_{VREF} in the UP direction (as shown in FIG. 5) in order to cause reference voltage generator 113 to change (e.g., increase) the value of voltage V_{REF} from 0.35V to 0.40V (which is the value of voltage V_{REF} associated with the MEP).

Decision logic 140 may hold (e.g., indicate by "HOLD") the value of ADJ_{VREF} in order to cause reference voltage generator 113 to hold the value of voltage (e.g., 0.40V) V_{REF} associated with the MEP after the value in memory 141 is changed to the value associated with the MEP. While the value of V_{REF} is held at the value associated with the MEP, digital energy monitor 130 continues to perform evaluation periods (e.g., 5 through 17) in order to calculate additional Eops (e.g., Eop5 through Eop17), and decision logic 140 continues to find (e.g., search for) a new MEP (e.g., a subsequent MEP after the initial MEP is found). If a new MEP is found (e.g., the MEP associated with Eop13) then decision logic 140 may perform an operation (e.g., operation 542) to update the value of Eop stored in memory 141 with the new value associated with the new MEP. For example, operation 542 may change value 12 uJ in memory 141 to 15.2 uJ.

After the new value associated with the new MEP is stored, decision logic 140 may repeat the process in order to find the next MEP (if any). For example, as shown in FIG. 5, decision logic 140 may hold (e.g., HOLD) the value of ADJ_{VREF} after operation 542 in order to cause reference voltage generator 113 to hold the value of voltage V_{REF} after it is changed to the value associated with the MEP. In this example, the value of V_{REF} is held at 0.35V.

The example above assumes that a new MEP is found at Eop13. However, if no MEP is found, the value (e.g., 12 uJ) of Eop3 may remain in memory 141.

Thus, as described above, decision logic 140 may store at least three (e.g., three or more) consecutive values of Eops (e.g., Eop2, Eop3, and Eop4 or Eop12, Eop13, and Eop14) during the operation of find the MEP. This allows decision logic 140 to compare a present energy value with previous energy values in order to determine whether the initial (or a subsequent) MEP is found.

Finding a subsequent MEP is described as follows. After a value of an initial MEP is found and stored, decision logic 140 monitors (e.g., by comparing) the value of each subsequent Eop (which is an Eop generated after the initial MEP is found) relative to the stored value (e.g., 12 uJ) in order to determine whether there is a relatively significant energy surge that may (or may not) produce a new MEP. A significant energy surge may be a strong indicator of higher switching activities; thereby a new MEP may exist. Decision logic 140 may perform a downward tracking (e.g., downward searching) operation to find a new MEP if a relatively

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significant energy surge occurs. The downward tracking operation is similar to the operations associated with Eop2, Eop3, and Eop4.

For example, decision logic **140** may compare each subsequent Eop with an upper energy threshold $E_{upper} = Eop_Stored + Eth$. Component Eop_Stored is the value (e.g., 12 uJ) associated the MEP and is stored in memory **141**. Component Eth is an energy threshold level having a selected value (e.g., a predetermined value) based on expected increased (or decrease) in the amount of energy at node **122** (FIG. 1) when some events may cause a significant energy surge (or drop) at node **122**. The value of component Eth can be selected during design (e.g., before fabrication) of an IC chip that includes voltage controller **110**. However, the value of component Eth may also be programmable (e.g., selected after fabrication of the IC chip that includes voltage controller **110**). In the example of FIG. 5, the value of component Eth is assumed to be selected (e.g., set) at 5 uJ. Other values for component Eth may be used. Thus, in the example of FIG. 5, decision logic **140** monitors the value of Eop (generated after the initial MEP is found) in order to determine whether a particular average energy per operation (e.g., a surge) is greater than the value of E_{upper} (which is $Eop_Stored + Eth$). As shown in FIG. 5, $Eop_{12} (0.40V) = 17.6$ uJ is greater than $E_{upper} = 12$ uJ + 5 uJ. Thus, in this example, decision logic **140** may follow the pattern of operations of decision logic **140** described above (e.g., Eop2, Eop3, and Eop4) and perform an upward tracking (e.g., upward searching) operation and determine that a new MEP is found. This new MEP is associated with $Eop_{13} (0.35V) = 15.2$ uJ. Thus, as described above, decision logic **140** performs operation **542** to update the content of memory **141** with 15.2 uJ.

The example above describes operations where decision logic **140** detects whether there is a significant energy surge (e.g., whether a subsequent $Eop > E_{upper}$, where $E_{upper} = Eop_Stored + Eth$). However, decision logic **140** may also operate to detect whether there is significant energy drop that may (or may not) produce a new MEP. For example, decision logic **140** may detect whether a particular Eop is less than a lower energy threshold E_{lower} (e.g., whether a subsequent $Eop < E_{lower}$, where $E_{lower} = Eop_Stored - Eth$). Decision logic **140** may perform a downward tracking operation to find a new MEP if a relatively significant energy drop occurs.

Thus, as described above, decision logic **140** may receive the average energy per operation calculated by digital energy monitor **130** and dynamically adjust the value of voltage V_{REF} in order to track the MEP of voltage controller **110** and load **115**. The tracking of MEP may be performed without workload information (e.g., without input from load **115**). Instead, the tracking of MEP may be based on monitoring whether a significant surge (or drop) in energy exceeds an energy threshold level (e.g., Eth).

FIG. 6 is a flow diagram showing a method **600** operating an electronic apparatus (e.g., a method of determining MEP in a voltage controller and a load), according to some embodiments described herein. The voltage controller and a load associated with method **600** can include voltage controller **110** and load **115** of apparatus **100** of FIG. 1. Method **600** may be performed by voltage controller **110** of FIG. 1. Some or all of activities in method **600** may be performed by hardware, software, or firmware, or any combination of hardware, software, and firmware.

As shown in FIG. 6, activity **610** of method **600** may include starting an initial search for the MEP voltage controller and a load. The initial search may include a down-

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ward searching operation. In activity **610**, the value (e.g., initial value) of V_{REF} may be set as $V_{REF} = 1.2 \times V_{th}$. The direction for the value of information ADJ_{VREF} can be set to be in the DOWN direction (e.g., in order to perform an initial downward searching operation).

Activity **620** can include generating voltage V_{REF} . Activity **620** can be performed by a reference voltage generator (e.g., reference voltage generator **113** of FIG. 1). In FIG. 6, V_{REF_K} , V_{REF_K-1} , and V_{REF_K-2} represent three different values of voltage V_{REF} generated by the reference voltage generator at three different times. For example, V_{REF_K-1} is generated after V_{REF_K} is generated, and V_{REF_K-2} is generated after V_{REF_K-1} is generated. V_{REF} can be the present value of V_{REF} , V_{REF_K-1} can be the previous value (e.g., old value) of V_{REF} , and V_{REF_K-2} can be another previous value (oldest value) of V_{REF} among V_{REF_K} , V_{REF_K-1} , and V_{REF_K-2} .

Activity **620** can include controlling (e.g., increasing, decreasing, or keeping the same (or holding)) the value of V_{REF} each time activity (e.g., routine) **621** or **622** is performed (described below). For example, activity **620** can hold the value of V_{REF} if activity **621** or **622** is performed (described below) and if the value of ADJ_{VREF} (described below) corresponds to the HOLD direction. In another example, activity **620** can decrease the value of V_{REF} if activity **621** or **622** is performed and if the value of ADJ_{VREF} corresponds to the DOWN direction. In another example, activity **620** can increase the value of V_{REF} if activity **621** or **622** is performed and if the value of ADJ_{VREF} corresponds to the UP direction. As an example, if V_{REF_K} is a present value, then activity **620** can generate a new V_{REF_K} ; the old V_{REF_K} becomes V_{REF_K-1} if activity **621** or **622** is performed and if the value of ADJ_{VREF} corresponds to UP or DOWN direction. At a later time in this example, V_{REF_K-1} can become V_{REF_K-2} and the new V_{REF} (previously generated) can become V_{REF_K-1} if activity **620** generates another new V_{REF_K} when activity **621** or **622** is performed and the value of ADJ_{VREF} corresponds to UP or DOWN direction.

Activity **630** can include calculating energy consumption of the voltage controller and the load. Activity **630** can be performed by a digital energy monitor (e.g., digital energy monitor **130** of FIG. 1 and **430** of FIG. 4). Activity **630** can include calculating average energy per operation Eop at a particular value of voltage V_{REF} . FIG. 6 shows three different average energy per operations Eop (V_{REF_K}), Eop (V_{REF_K-1}), and Eop (V_{REF_K-2}) that are calculated (e.g., sequentially) during three different evaluation periods at three different values of V_{REF} , respectively. Each evaluation period can be N cycles (e.g., 1000 cycles of the CLK signal). For example, activity **630** can calculate Eop (V_{REF_K}) in N cycles, calculate Eop (V_{REF_K-1}) in the next N cycles after Eop (V_{REF_K}) is calculated, and then calculate Eop (V_{REF_K-2}) in another N cycles after Eop (V_{REF_K-1}) is calculated.

Eop (V_{REF_K}) can be the present value of the average energy per operation, Eop (V_{REF_K-1}) can be the previous value (e.g., old value) of the average energy per operation, and Eop (V_{REF_K-2}) can be another previous value (oldest value) of the average energy per operation.

Method **600** can include portion **640** that can be performed by a decision logic (e.g., decision logic **140** of FIG. 1). Based on the average energy per operations (e.g., Eop (V_{REF_K}), Eop (V_{REF_K-1}), Eop (V_{REF_K-2})) calculated in activity **630**, portion **640** of method **600** cause (e.g., by performing activity **621** or **622**) activity **620** to adjust the value of V_{REF} in order to determine the MEP in the voltage controller and load associated with method **600**.

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Activity **642** of portion **640** can include determining whether $V_{REF} > V_{min}$ (where V_{min} can be the minimum value of an operating voltage (e.g., V_{OUT}) of the load).

In activity **642**, if $V_{REF} > V_{min}$ is not true (V_{REF} is not greater than V_{min} , indicated as “N”), then the value of the MEP can be set to be the present value (e.g., V_{REF_K}) of voltage V_{REF} . The MEP in activity **642**, however, may or may not correspond to the local minima. Activity **644** can set $Eop_Stored = Eop(V_{REF_K})$, where Eop_Stored is the value (e.g., in uJ unit) stored in a memory (e.g., such as memory **141** of FIG. **5**). In this case, activity **644** can also set the value of information ADJ_{VREF} to be corresponding to the HOLD direction in order to cause (through activity **621**) activity **620** to hold the value of V_{REF} at V_{REF_K} .

In activity **642**, if $V_{REF} > V_{min}$ is true (V_{REF} is greater than V_{min} , indicated as “Y”), method **600** can continue with activity **646**, which can check whether $ADJ_{VREF} = HOLD$.

In activity **646**, if $ADJ_{VREF} = HOLD$ is not true, method **600** can continue with at least one of activities **660** through **667**, as described below.

In activity **646**, if $ADJ_{VREF} = HOLD$ is true (indicated as “Y”), method **600** can continue with activity **648**.

Activity **648** can check whether $Eop(V_{REF_K}) > Eop_Stored + Eth$. As described above, component Eth is an energy threshold level used to determine whether a significant energy surge (or drop) may occur. In activity **648**, if $Eop(V_{REF_K}) > Eop_Stored + Eth$ is true (indicated as “Y”), method **600** can continue with activity **650** to set $ADJ_{VREF} = DOWN$ to cause (through activity **621**) activity **620** to decrease the value of V_{REF} . If $Eop(V_{REF_K}) > Eop_Stored + Eth$ is not true (indicated as “N”), method **600** can continue with activity **652**.

Activity **652** can check whether $Eop(V_{REF_K}) < Eop_Stored - Eth$. If $Eop(V_{REF_K}) < Eop_Stored - Eth$ is true (indicated as “Y”), method **600** can continue with activity **654** to set $ADJ_{VREF} = UP$ to cause (through activity **621**) activity **620** to increase the value of V_{REF} . If $Eop(V_{REF_K}) < Eop_Stored - Eth$ is not true (indicated as “N”), method **600** can continue with at least one of activities **660** through **667**.

Method **600** can perform activities **660** through **667** to find the MEP of the voltage controller and the load. For example, method **600** can perform activities **660** through **665** to compare the values of different average energy per operations $Eop(V_{REF_K})$, $Eop(V_{REF_K-1})$, and $Eop(V_{REF_K-2})$.

Based on the results of the comparisons, if the MEP is not found, method **600** can cause the value of V_{REF} to increase or decrease and continue searching for the MEP. As shown in FIG. **6**, method **600** may perform either an upward searching operation (e.g., based on the value of $ADJ_{VREF} = UP$ in activity **661**) or a downward searching operation (e.g., based on the value of $ADJ_{VREF} = DOWN$ in activity **663**).

In activity **665**, when the MEP is found (which can correspond to the local minima), activity **665** can set $Eop_Stored = Eop(V_{REF_K-1})$, where $Eop(V_{REF_K-1})$ is the previous average energy per operation. Setting $Eop_Stored = Eop(V_{REF_K-1})$ can include updating the stored value of average energy per operation value in memory (e.g., memory **141**) with a new value of average energy per operation.

In activity **665**, when the MEP is found, activity **665** can also set $V_{REF_K} = V_{REF_K-1}$ (e.g., by setting the value of information ADJ_{VREF} to be corresponding to the UP direction, not shown in activity **665**). After setting $V_{REF_K} = V_{REF_K-1}$ (e.g., after setting the value of information ADJ_{VREF} to be corresponding to the UP direction),

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activity **665** can set the value of information ADJ_{VREF} to be corresponding to the HOLD direction, as shown in activity **665**. After the MEP is found in activity **665**, method **600** can continue searching for another MEP through activity **622** and repeat the activities of method described above.

As shown in FIG. **600**, method **600** can include activity **667** to indicate that an error occurs and then executes the initial search (e.g., downward search in activity **610**). For example, if the condition in activity **666** is true (indicated by Y), method **600** can continue with activity **667** and then go to activity **610** and execute the initial search in activity **610** and other activities of method **600**, as described above.

Method **600** can include additional activities (e.g., operations) of a memory device described above with reference to FIG. **1** through FIG. **5**.

The illustrations of apparatus (e.g., apparatus **100**) and methods (e.g., method **600**, and the operations of voltage controller **110** described above with reference to FIG. **1** through FIG. **5**) are intended to provide a general understanding of the structure of various embodiments and are not intended to provide a complete description of all the elements and features of apparatuses that might make use of the structures described herein.

The apparatus (e.g., apparatus **100**) described herein may include or be included in electronic circuitry, such as high-speed computers, communication and signal processing circuitry, single or multi-processor modules, single or multiple embedded processors, multi-core processors, message information switches, and application-specific modules including multilayer, multi-chip modules. Such apparatuses may further be included as sub-components within a variety of other apparatuses (e.g., electronic systems), such as televisions, cellular telephones, personal computers (e.g., laptop computers, desktop computers, handheld computers, tablet computers, etc.), workstations, radios, video players, audio players (e.g., MP3 (Motion Picture Experts Group, Audio Layer 5) players), vehicles, medical devices (e.g., heart monitor, blood pressure monitor, etc.), set top boxes, and others.

Additional Notes and Examples

Example 1 includes subject matter (such as a device, an electronic apparatus (e.g., circuit, electronic system, or both), or a machine) including a power switching unit to receive a first voltage and provide a second voltage having a value based on a value of the first voltage, a first loop to provide digital control information to control a switching of the power switching unit in order to maintain a relationship between a value of the second voltage and a value of a reference voltage, and a second loop coupled to the power switching unit and the first loop to calculate a value of energy consumption of at least a portion of the apparatus based at least on the digital control information.

In Example 2, the subject matter of Example 1 may optionally include, wherein the power switching unit is included in a low-drop out (LDO) voltage controller, and the first and second loops are embedded in the LDO voltage controller.

In Example 3, the subject matter of Example 1 may optionally include, wherein the second loop is arranged to adjust the value of the reference voltage based on the value of the energy consumption.

In Example 4, the subject matter of Example 1 may optionally include, wherein the second loop is arranged to adjust the value of the reference voltage based on the value

of the energy consumption in order to track minimum energy point (MEP) of the portion of the apparatus.

In Example 5, the subject matter of any of Examples 1-4 may optionally include, wherein the value of the energy consumption is an average energy per cycle of a total energy consumption calculated over a number of cycles of a clock signal clock.

In Example 6, the subject matter of any of Examples 1-2 may optionally include, wherein the second loop is arranged to find a minimum energy point (MEP) based on the value of the energy consumption.

In Example 7, the subject matter of any of Examples 1-2 may optionally include, wherein the second loop is arranged to perform math operations to calculate the value of the energy consumption, the math operations including a subtraction operation.

In Example 8, the subject matter of any of Examples 1-2 may optionally include, wherein the second loop is arranged to change the value of the reference voltage from a first value to a second value, and the first loop is arranged to maintain the relationship between the value of the second voltage with each of the first and second values of the reference voltage.

Example 9 includes subject matter (such as a device, an electronic apparatus (e.g., circuit, electronic system, or both), or a machine) including a first node to receive a first voltage having a first value, a second node to provide a second voltage having a second value less than the first value, a power switching unit coupled between the first and second nodes, a comparator to provide information based on a comparison between the second value and a value of a reference voltage, a control unit to provide digital control information based on the information provided by the comparator to control the power switching unit, a digital energy monitor to calculate a value of energy consumption of at least a portion of the apparatus based on digital values derived from at least the first value and a value of the digital control information from the control unit, and a decision logic to adjust the value of the reference voltage based on the value of the energy consumption.

In Example 10, the subject matter of Example 9 may optionally include, wherein the decision logic is arranged to track a minimum energy point (MEP) of the at least a portion of the apparatus based on the value of the energy consumption.

In Example 11, the subject matter of any of Examples 9-10 may optionally include, wherein the power switching unit include transistors arranged in parallel between the first and second nodes.

In Example 12, the subject matter of Example 11 may optionally include, wherein the control unit is arranged to provide digital information including bits, and each of the bits is provided to a gate of a respective transistor among the transistors.

In Example 13, the subject matter of any of Examples 9-10 may optionally include, wherein the digital energy monitor includes circuitry to perform math operations to calculate the value of the energy consumption.

In Example 14, the subject matter of Example 9 may optionally include, wherein the decision logic is arranged to cause the value of the reference voltage to change from one value to another value based on a minimum energy point (MEP) associated with the value of the energy consumption.

In Example 15, the subject matter of Example 9 may optionally include, wherein the decision logic is arranged to perform an operation to find a minimum energy point (MEP)

based on the value of the energy consumption, and to change the value of the reference voltage one value to another value when the MEP is found.

In Example 16, the subject matter of any of Examples 9-10 may optionally include, further comprising a die, wherein the power switching unit, the comparator, the control unit, the digital energy monitor, and the decision logic are included in the die.

Example 17 includes subject matter (such as a device, an electronic apparatus (e.g., circuit, electronic system, or both), or a machine) including a processing unit, and a low-drop out (LDO) voltage controller coupled to the processing core, the low-drop out voltage controller including a power switching unit to receive a first voltage and provide a second voltage having a value based on a value of the first voltage, a first loop to provide digital control information to control a switching of the power switching unit in order to maintain a relationship between the value of the second voltage and a value of a reference voltage, and a second loop coupled to the power switching unit and the first loop to calculate a value of energy consumption of at least a portion of the apparatus based at least on the digital control information.

In Example 18, the subject matter of Example 17 may optionally include, wherein further comprising a die, wherein the processing unit and the LDO voltage controller are included in the die.

In Example 19, the subject matter of Example 17 may optionally include, further comprising a die, wherein the LDO voltage controller is included in the die, and the processing unit is located outside the die.

In Example 20, the subject matter of any of Examples 17-19 may optionally include, wherein the second loop is arranged to adjust the value of the reference voltage based on the value of the energy consumption.

Example 21 includes subject matter (such as a method of operating a device, an electronic apparatus (e.g., circuit, electronic system, or both), or a machine) including receiving digital values at a digital energy monitor of a low-drop out (LDO) voltage controller, the LDO voltage controller including transistors coupled in parallel between a first node and a second node of the LDO voltage controller, maintaining a relationship between a voltage at the second node and a reference voltage, calculating a value of energy consumption of operation consumed by at least a load coupled to the second node based on the digital values, and adjusting a value of a reference voltage based on the value of energy consumption to track a minimum energy point (MEP) associated with at least the load.

In Example 22, the subject matter of Example 21 may optionally include, wherein calculating the value of the energy consumption includes calculating a number of average energy per operation.

In Example 23, the subject matter of any of Examples 21-22 may optionally include, wherein finding the MEP including storing a first value of energy consumption if a first MEP is found, and replacing the first value of energy consumption with a second value of energy consumption if a second MEP is found.

In Example 24, the subject matter of any of Examples 21-22 may optionally include, wherein adjusting the value of the reference voltage includes comparing the value of energy consumption with a stored value of energy consumption, and changing the value of the reference voltage if a difference between the value of the energy consumption and the stored value of energy consumption exceed a selected value.

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In Example 25, the subject matter of any of Examples 21-22 may optionally include, wherein adjusting the value of the reference voltage includes changing the value of the reference voltage from a first value to a second value, wherein the first value is less than the second value.

In Example 26, the subject matter of any of Examples 21-22 may optionally include, wherein adjusting the value of the reference voltage includes changing the value of the reference voltage from a first value to a second value, wherein the first value is greater the second value.

Example 27 includes subject matter (such as a device, an electronic apparatus (e.g., circuit, electronic system, or both), or machine) including means for performing any of the methods of examples 21-26.

The subject matter of Example 1 through Example 27 may be combined in any combination.

The above description and the drawings illustrate some embodiments to enable those skilled in the art to practice the embodiments of the invention. Other embodiments may incorporate structural, logical, electrical, process, and other changes. Examples merely typify possible variations. Portions and features of some embodiments may be included in, or substituted for, those of other embodiments. Many other embodiments will be apparent to those of skill in the art upon reading and understanding the above description. Therefore, the scope of various embodiments is determined by the appended claims, along with the full range of equivalents to which such claims are entitled.

The Abstract is provided to comply with 37 C.F.R. Section 1.72(b) requiring an abstract that will allow the reader to ascertain the nature and gist of the technical disclosure. It is submitted with the understanding that it will not be used to limit or interpret the scope or meaning of the claims. The following claims are hereby incorporated into the detailed description, with each claim standing on its own as a separate embodiment.

What is claimed is:

1. An apparatus comprising:

a power switching unit to receive a first voltage and provide a second voltage having a value based on a value of the first voltage;

a first loop to provide digital control information to control a switching of the power switching unit in order to maintain a relationship between a value of the second voltage and a value of a reference voltage; and
a second loop coupled to the power switching unit and the first loop to receive the digital control information from the first loop and to calculate a value of energy consumption of at least a portion of the apparatus based at least on the digital control information, wherein the power switching unit is included in a low-drop out (LDO) voltage controller, and the first and second loops are embedded in the LDO voltage controller.

2. The apparatus of claim 1, wherein the second loop is arranged to adjust the value of the reference voltage based on the value of the energy consumption.

3. The apparatus of claim 1, wherein the second loop is arranged to adjust the value of the reference voltage based on the value of the energy consumption in order to track minimum energy point (MEP) of the portion of the apparatus.

4. The apparatus of claim 1, wherein the value of the energy consumption is an average energy per cycle of a total energy consumption calculated over a number of cycles of a clock signal clock.

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5. The apparatus of claim 1, wherein the second loop is arranged to find a minimum energy point (MEP) based on the value of the energy consumption.

6. The apparatus of claim 1, wherein the second loop is arranged to perform math operations to calculate the value of the energy consumption, the math operations including a subtraction operation.

7. The apparatus of claim 1, wherein the second loop is arranged to change the value of the reference voltage from a first value to a second value, and the first loop is arranged to maintain the relationship between the value of the second voltage with each of the first and second values of the reference voltage.

8. An apparatus comprising:

a first node to receive a first voltage having a first value;
a second node to provide a second voltage having a second value less than the first value;

a power switching unit coupled between the first and second nodes;

a comparator to provide information based on a comparison between the second value and a value of a reference voltage;

a control unit to provide digital control information based on the information provided by the comparator to control the power switching unit;

a digital energy monitor to calculate a value of energy consumption of at least a portion of the apparatus based on digital values derived from at least the first value and a value of the digital control information from the control unit; and

a decision logic to adjust the value of the reference voltage based on the value of the energy consumption, wherein the power switching unit, the comparator, the control unit, the digital energy monitor, and the decision logic are included in a low-drop out (LDO) voltage controller.

9. The apparatus of claim 8, wherein the decision logic is arranged to track a minimum energy point (MEP) of the at least a portion of the apparatus based on the value of the energy consumption.

10. The apparatus of claim 8, wherein the power switching unit includes transistors arranged in parallel between the first and second nodes.

11. The apparatus of claim 10, wherein the control unit is arranged to provide digital information including bits, and each of the bits is provided to a gate of a respective transistor among the transistors.

12. The apparatus of claim 8, wherein the digital energy monitor includes circuitry to perform math operations to calculate the value of the energy consumption.

13. The apparatus of claim 8, wherein the decision logic is arranged to cause the value of the reference voltage to change from one value to another value based on a minimum energy point (MEP) associated with the value of the energy consumption.

14. The apparatus of claim 8, wherein the decision logic is arranged to perform an operation to find a minimum energy point (MEP) based on the value of the energy consumption, and to change the value of the reference voltage one value to another value when the MEP is found.

15. The apparatus of claim 8, further comprising a die, wherein the power switching unit, the comparator, the control unit, the digital energy monitor, and the decision logic are included in the die.

- 16.** An apparatus comprising:
 a processing unit; and
 a low-drop out (LDO) voltage controller coupled to the
 processing core, the low-drop out voltage controller
 including: 5
 a power switching unit to receive a first voltage and
 provide a second voltage having a value based on a
 value of the first voltage;
 a first loop to provide digital control information to
 control a switching of the power switching unit in order 10
 to maintain a relationship between the value of the
 second voltage and a value of a reference voltage; and
 a second loop coupled to the power switching unit and the
 first loop to receive the digital control information from
 the first loop and to calculate a value of energy con- 15
 sumption of at least a portion of the apparatus based at
 least on the digital control information.
- 17.** The apparatus of claim **16**, further comprising a die,
 wherein the processing unit and the LDO voltage controller
 are included in the die. 20
- 18.** The apparatus of claim **16**, further comprising a die,
 wherein the LDO voltage controller is included in the die,
 and the processing unit is located outside the die.
- 19.** The apparatus of claim **16**, wherein the second loop is
 arranged to adjust the value of the reference voltage based 25
 on the value of the energy consumption.

* * * * *

UNITED STATES PATENT AND TRADEMARK OFFICE
CERTIFICATE OF CORRECTION

PATENT NO. : 10,108,212 B2
APPLICATION NO. : 14/861997
DATED : October 23, 2018
INVENTOR(S) : Park et al.

Page 1 of 1

It is certified that error appears in the above-identified patent and that said Letters Patent is hereby corrected as shown below:

In the Claims

Column 19, Line 48, Claim 1, delete “coup led” and insert --coupled-- therefor

Column 19, Lines 54-55, Claim 1, delete “loop s” and insert --loops-- therefor

Column 20, Line 34, Claim 8, delete “Dower” and insert --power-- therefor

Signed and Sealed this
Twenty-eighth Day of December, 2021



Drew Hirshfeld
*Performing the Functions and Duties of the
Under Secretary of Commerce for Intellectual Property and
Director of the United States Patent and Trademark Office*